



VTS-200 VCSEL Optical&Electrical Test System

Integrate VCSEL spectrum, radiation, temperature, electricity characteristics into one facility

Strong test function& high accuracy

The VTS-200 VCSEL photoelectric measurement and analysis system comprehensively evaluates the various photoelectric properties of VCSEL devices, with fast test speed, high accuracy, good stability, and powerful software functions, which can realize the measurement of the following parameters:

- Voltage, current, electrical power, optical power, photoelectric conversion efficiency
- Spectral power distribution curve, peak wavelength, half-width, center wavelength, etc.
- Radiation power, radiation efficiency
- LIV curve, radiation-temperature characteristic curve
- Threshold current
- PD current
- Differential resistance, slope efficiency

- Spectral range: 800-1000nm;
- Half-peak bandwidth: 0.2nm;
- Wavelength accuracy: 0.05nm;
- Temperature control method of temperature control fixture: TEC automatic temperature control, with an accuracy of 0.1°C (optional);
- PD current measurement can be realized (optional);
- Equipped with us-level and ns-level pulse power sources (according to customer requirements)

1) Us pulse power supply for VCSEL measurement

Programmable pulse output can be realized, with adjustable pulse width and duty cycle;

Pulse width: 100μs~30ms;

Duty ratio: 1%~90%;

Pulse constant current measurement range: 0~5A;

Pulse voltage measurement range: 0~5V;

Maximum output capacity: 5A/5V;

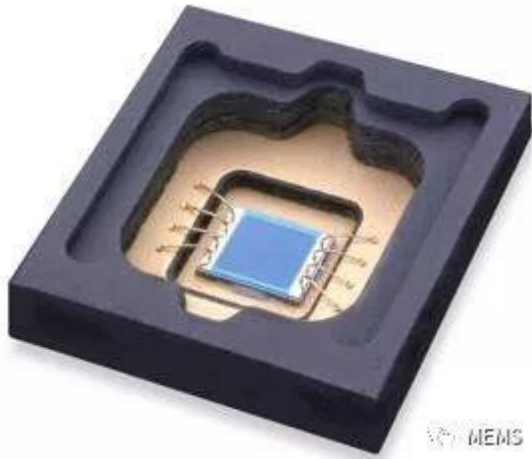
Voltage and current measurement accuracy: 0.2% of reading + 0.1% of range

2) ns pulse power supply for VCSEL measurement (optional)

Minimum pulse width: 1ns;

Peak current: 15A;

Repetition frequency: 100MHz



MEMS

